

SI3N4 SUBSTRATE FOR HYBRID / ELECTRIC VEHICLE DRIVE TRAIN INVERTER POWER MODULE

Design-to-cost Si3N4 Ag-free AMB Metal Ceramic Substrate

Habib Mustain, Heraeus Electronics – September 2022

OUTLINE

1 | Company overview

2 | Market trends for EV/HEV drivetrain
inverter applications

3 | Power module packaging trends for
automotive applications

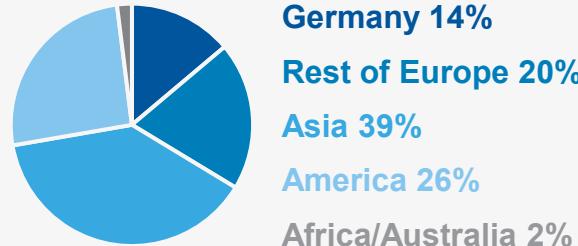
4 | Metal ceramic silicon nitride substrate

5 | Reliability results

6 | Summary

A GLOBALLY SUCCESSFUL PORTFOLIO COMPANY

 **29.5 bn. €
(34.9 bn. US\$)**
TOTAL REVENUE
in 2021



US\$ calculated with 2021 average exchange rate (1€ = 1.1827 US\$)

Region breakdown based on revenues excl. Precious Metals

12 market-oriented
GLOBAL BUSINESS UNITS

TOP 10
FAMILY-OWNED COMPANIES
in Germany

Listed in
FORTUNE
Global 500



More than
100 SITES in
40 COUNTRIES



Approx.
16,200
EMPLOYEES
in 2021



6% expenditures
for RESEARCH &
DEVELOPMENT

based on revenues excl. Precious Metals



BUSINESS PORTFOLIO – LEADING IN GLOBAL MARKETS



Heraeus
Comvance



Heraeus
Conamic



Heraeus
Electro-Nite



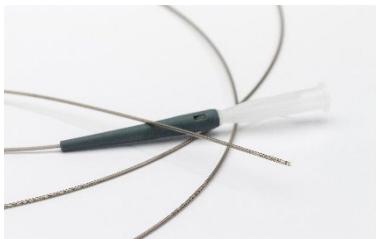
Heraeus
Electronics



Heraeus
Epurio



Heraeus
Medical



Heraeus
Medical
Components



Heraeus
Nexenos



Heraeus
Noblelight



Heraeus
Photovoltaics

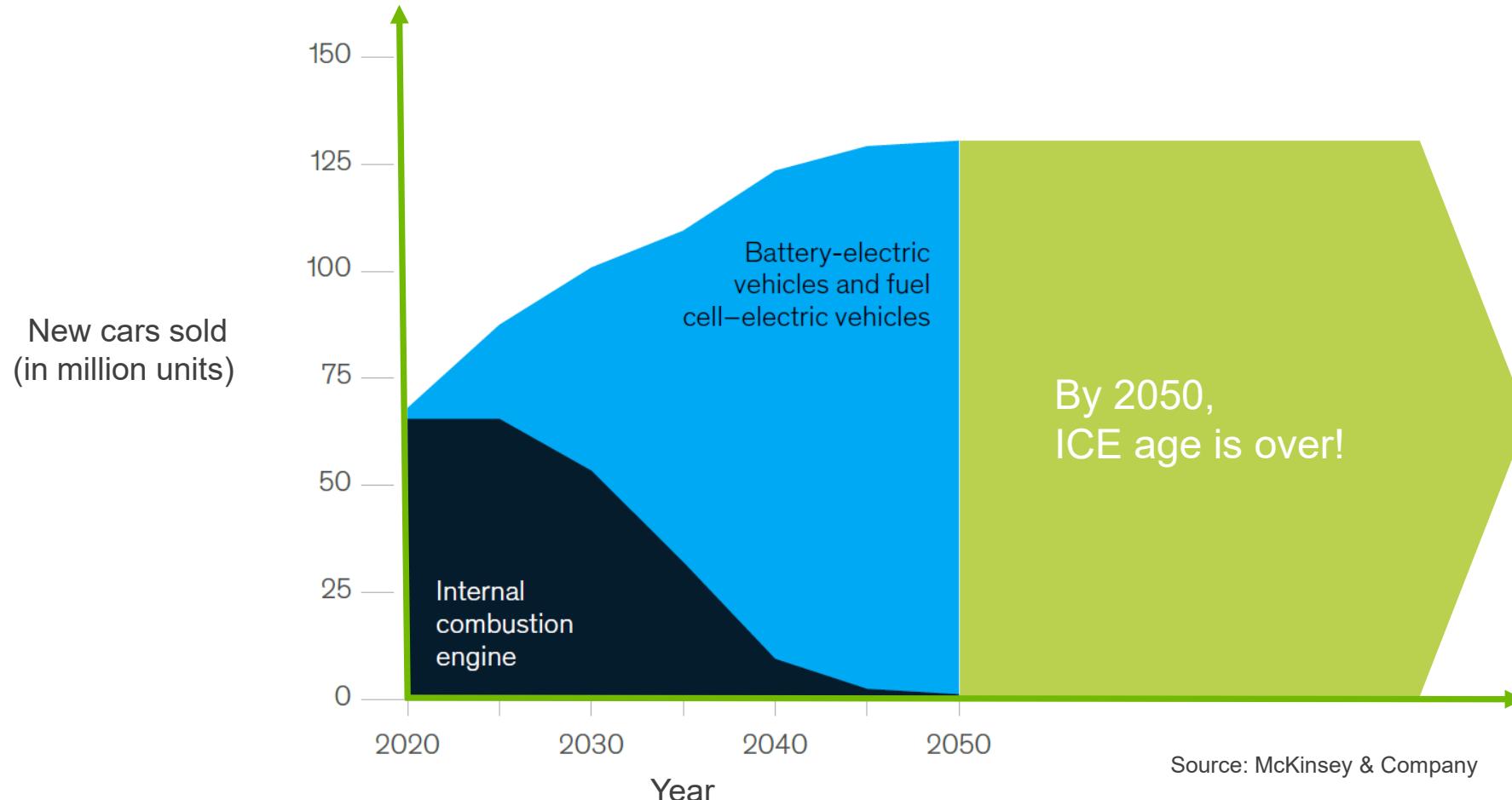


Heraeus
Precious
Metals

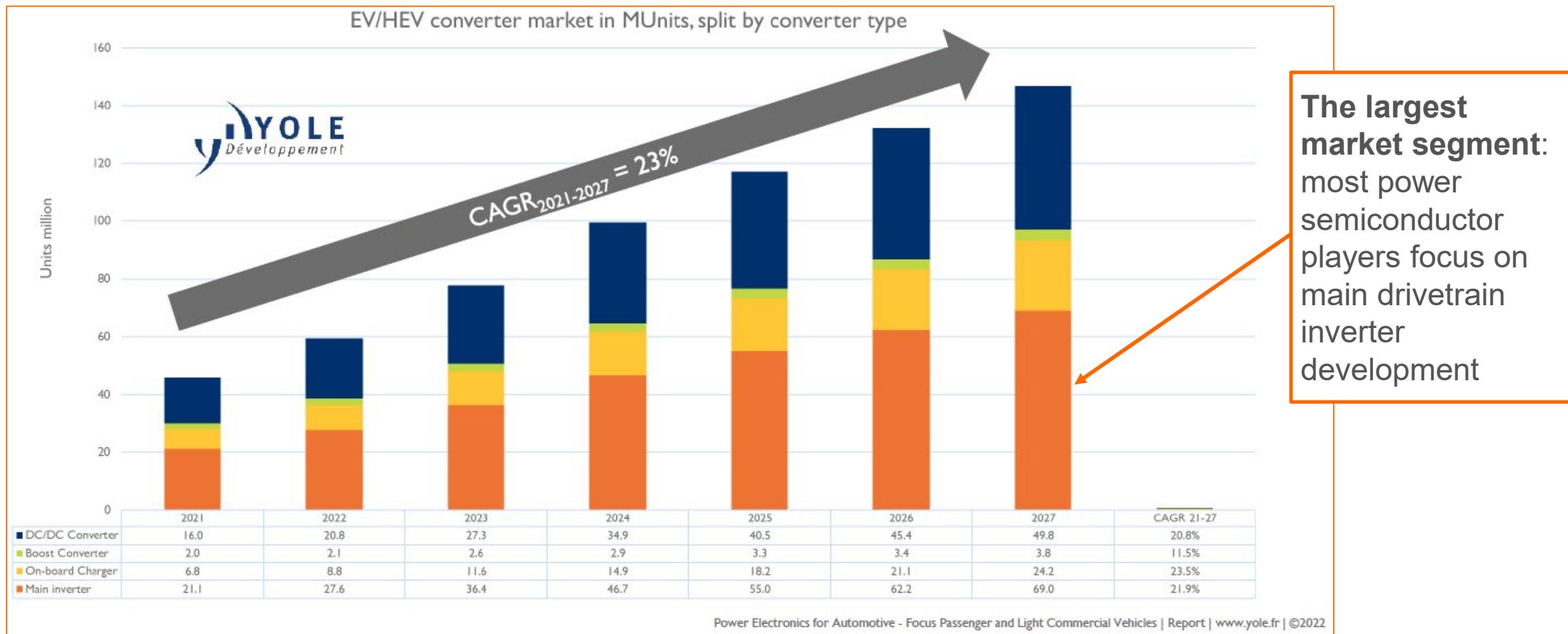


Norwood
Medical

MARKET TRENDS



2021-2027 GLOBAL XEV CONVERTER MARKET SPLIT BY DEVICE TYPE



POWER MODULE PACKAGING TRENDS IN AUTOMOTIVE APPLICATIONS



Power Module

- Many custom designs
- Technology challenges



Overmolded Module

- Fewer chips in module
- Flexibility in system design and size
- Less investment
- Scalability
- Adopt discrete device supply chain, manufacturing processes and tools

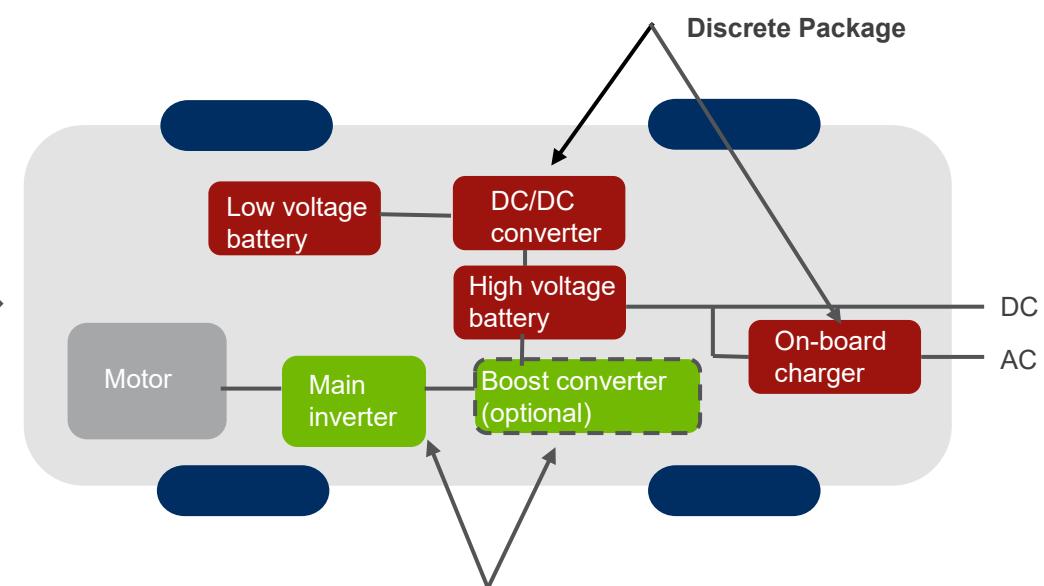


Discrete Package

- High level of standardization
- High volume manufacturing

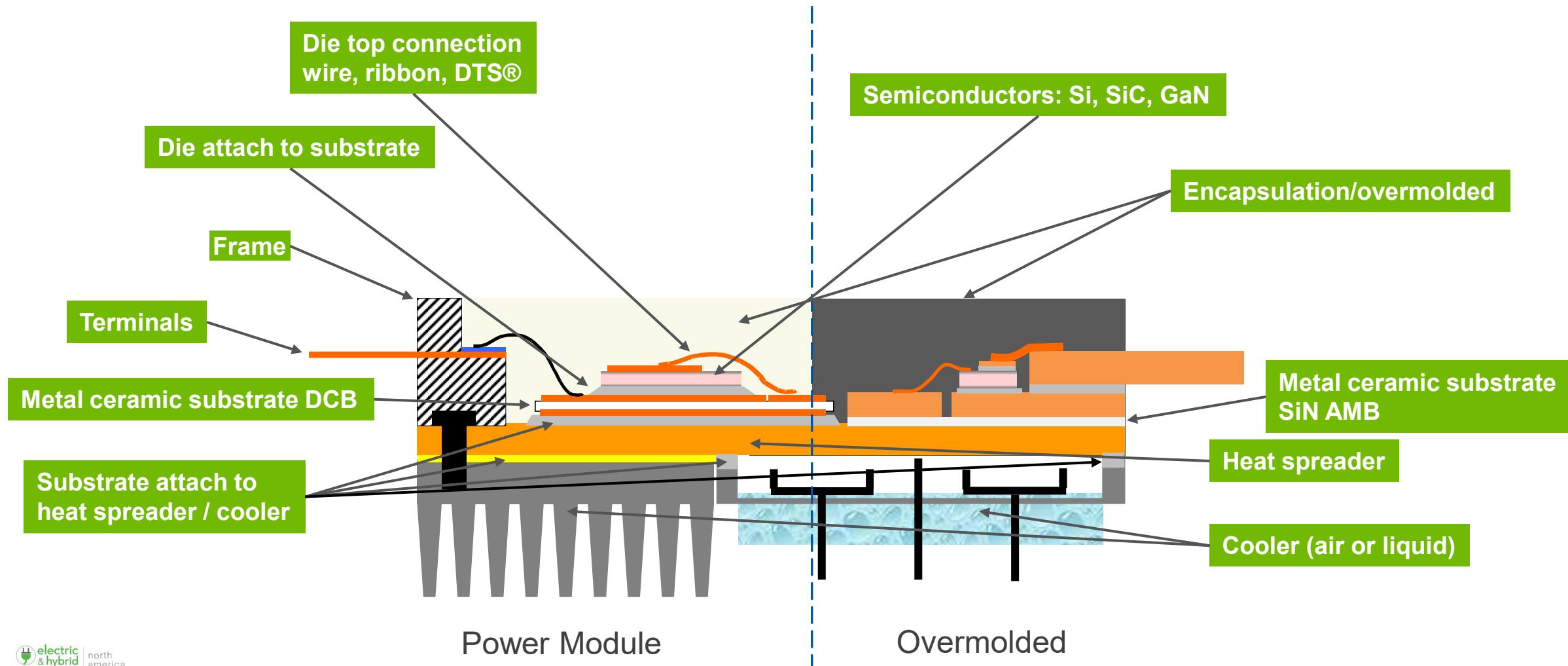


Battery/Hybrid Electric Vehicle



Power Module/overmolded mainly used

PACKAGING MATERIALS IN POWER MODULES



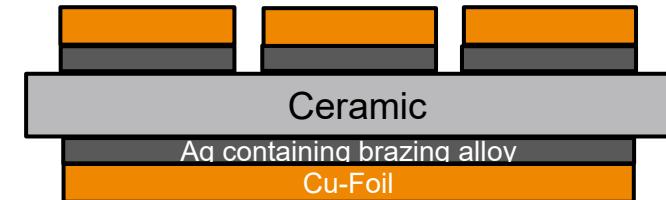
Si₃N₄ WITH OVERALL BEST PERFORMANCE, CHALLENGE: COST EFFECTIVENESS

	Al ₂ O ₃	ZTA	Si ₃ N ₄
Thermal conductivity	0	0	++
Bonding process (Cu)	DCB	DCB	AMB
Substrate reliability	0	+	+++
Cu layer thickness	-	0	+++
Substrate cost	+++	++	-

DCB: Direct copper bonding



AMB: Active metal brazing

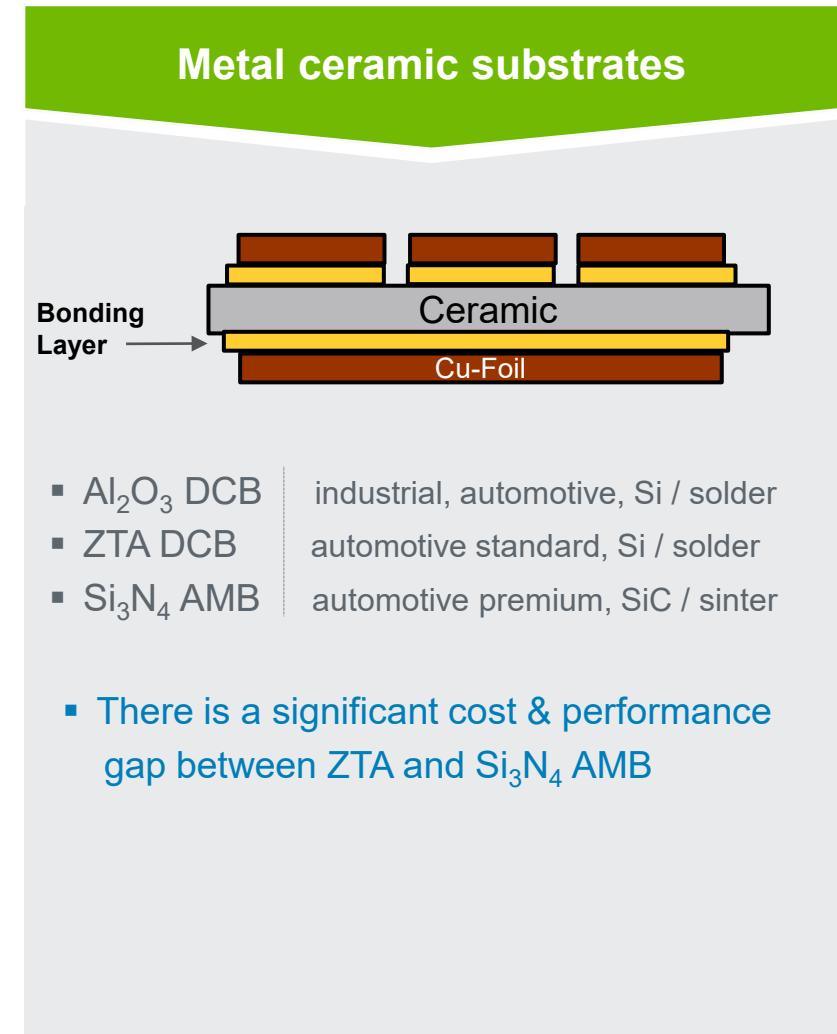
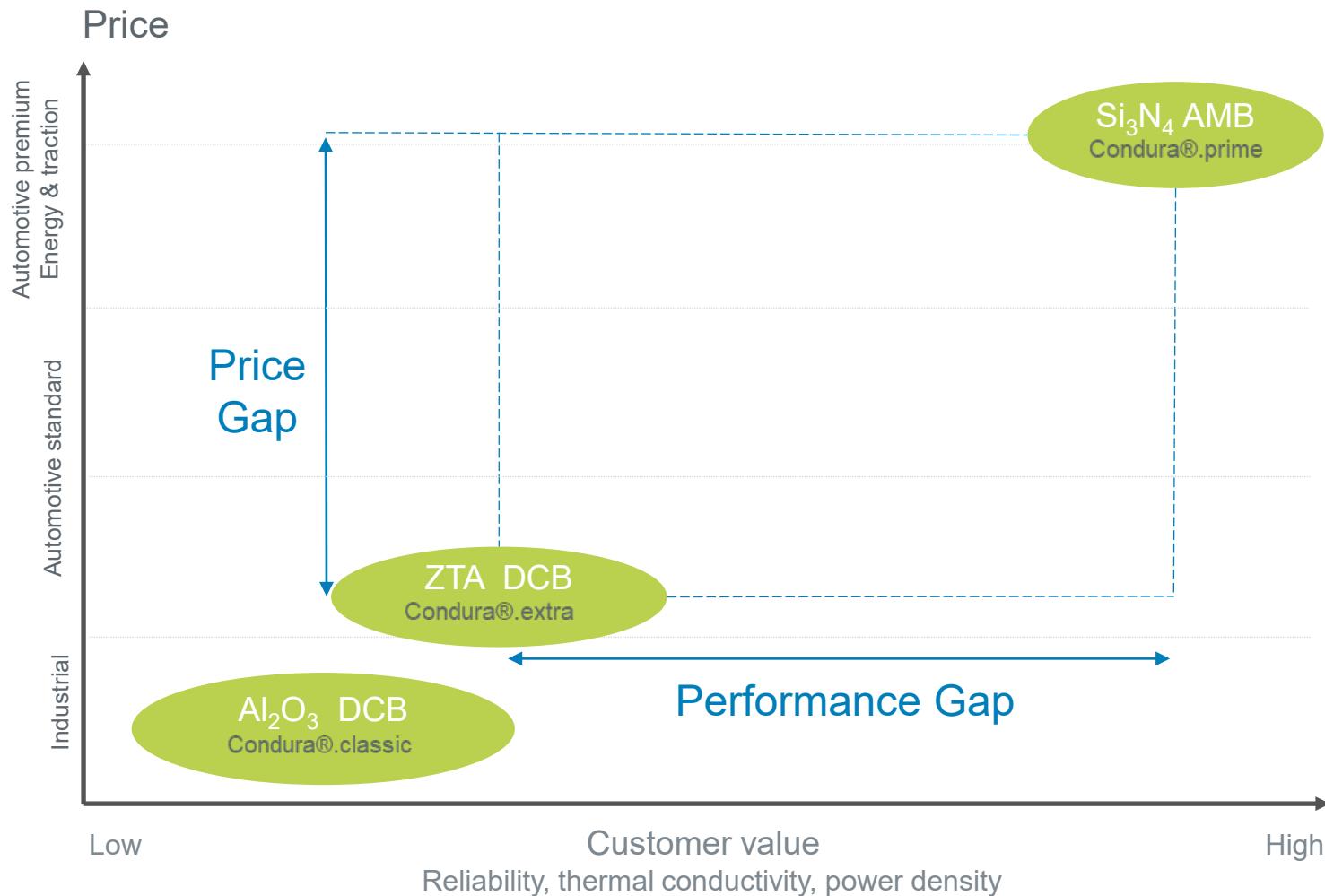


- Oxide based MCS offers sufficient reliability at moderate cost
 - Manufactured by DCB process
- Si₃N₄ based MCS are typically manufactured by AMB process using Ag based brazing pastes
- Si₃N₄ based MCS offer high reliability but cost effectiveness is a challenge
- Heraeus Electronics addresses this gap by **Ag free Si₃N₄ AMB technology**

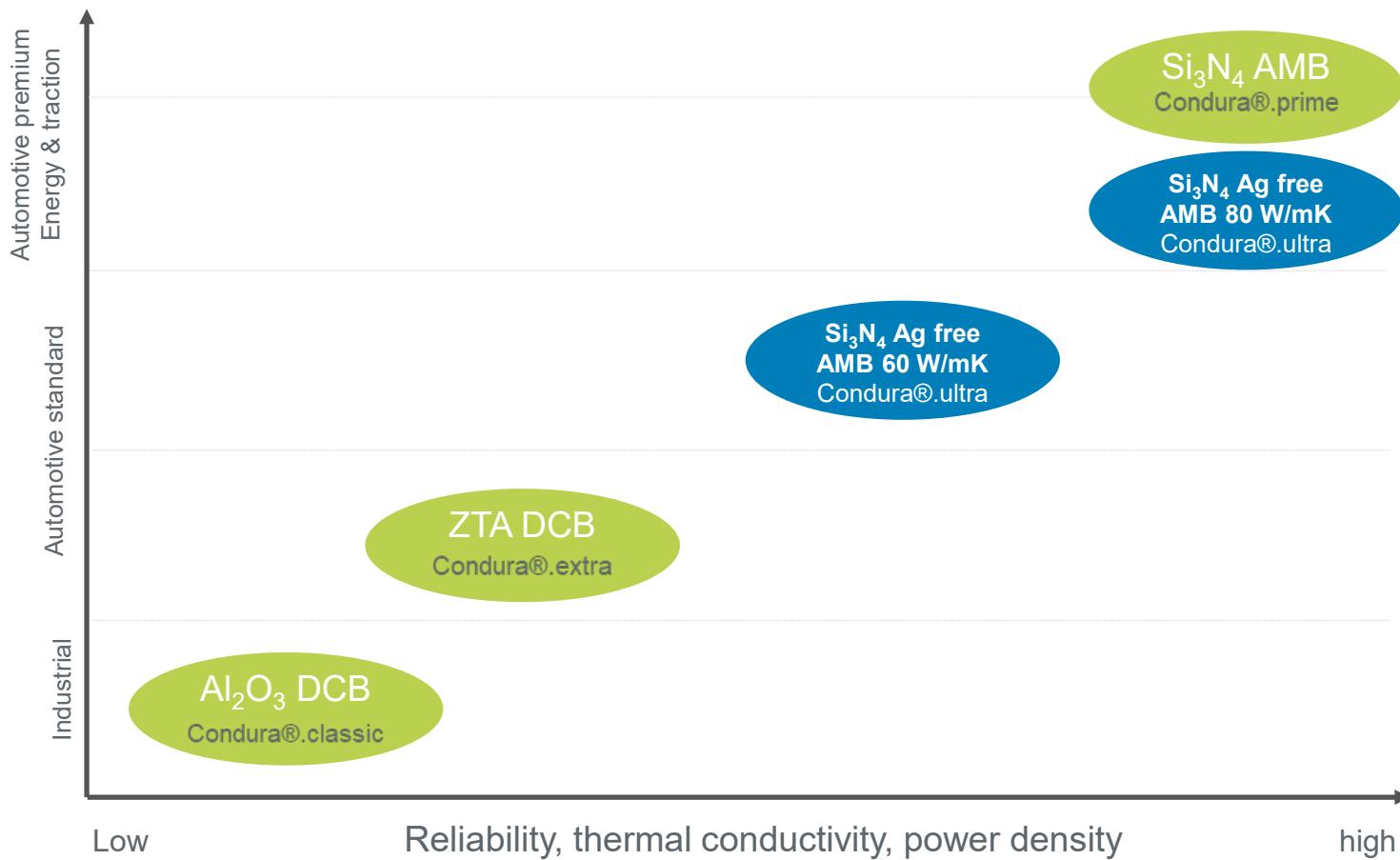
Source:

Challenges of New Packaging Solutions for Power Modules, Prof. R. Eisele FH Kiel, Anton Miric HDE, PCIM Conference May 2021
Silver-free thick film copper bonding for highly reliable metal ceramic substrates, Dr. Andre Schwöbel HDE, CIPS Conference 2022

STANDARD MCS POSITIONING



PRODUCT POSITIONING FOR Si_3N_4 AG FREE AMB®



Meeting Market Needs

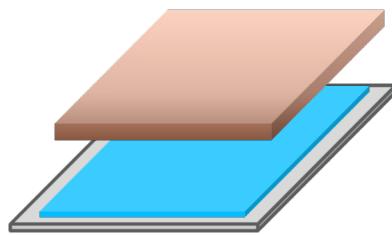
- Si_3N_4 is the ceramic material of choice for advanced metal ceramic substrates in automotive
 - Si_3N_4 Ag free AMB 80 W/mK offers AMB standard performance with commercial benefits
 - Si_3N_4 Ag free AMB 60 W/mK offers AMB standard performance with tailored Rth “Design to cost ceramic”

PRODUCTION OF NITRIDE CERAMIC-BASED SUBSTRATES

Paste print and stacking

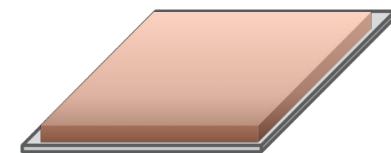
AMB

- › Nitride ceramic printed with active metal braze paste
- › Copper foil stacked on both sides



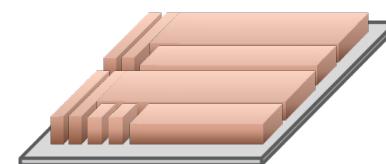
Bonding Process

- › Copper and ceramic stack fired in vacuum
- › Long process time



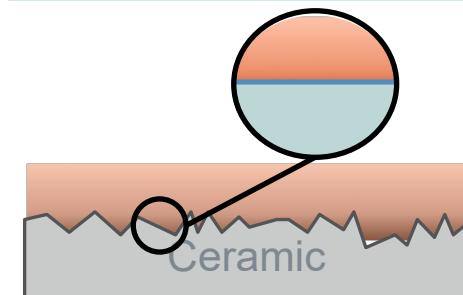
Finishing

- › Masking and etching
- › Laser scribing and surface finish



Conclusion

- › Ag-based brazing paste
- › Higher costs

Ag free
AMB

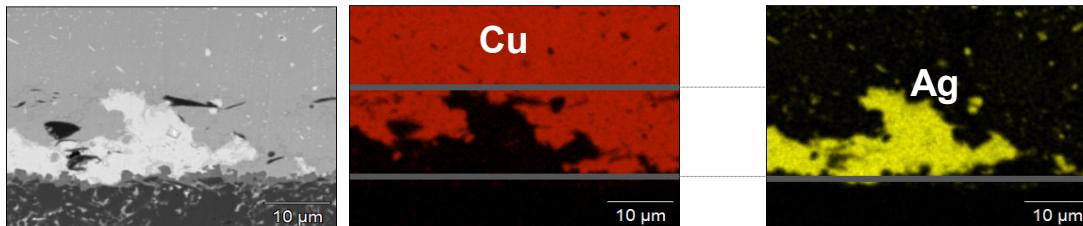
Heraeus AMB Process

- › Masking and etching
- › Laser scribing and surface finish

- › Ag-free process
- › Reduced costs
- › no Ag migration Risk

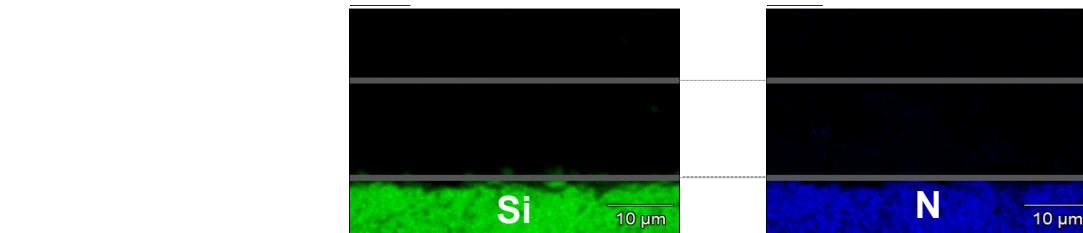
Source:
Silver-free thick film copper bonding for highly reliable metal ceramic substrates, Dr. Andre Schwöbel HDE, CIPS Conference 2022

MATERIAL MAPPING EDS (ENERGY DISPERITIVE SPECTROSCOPY)



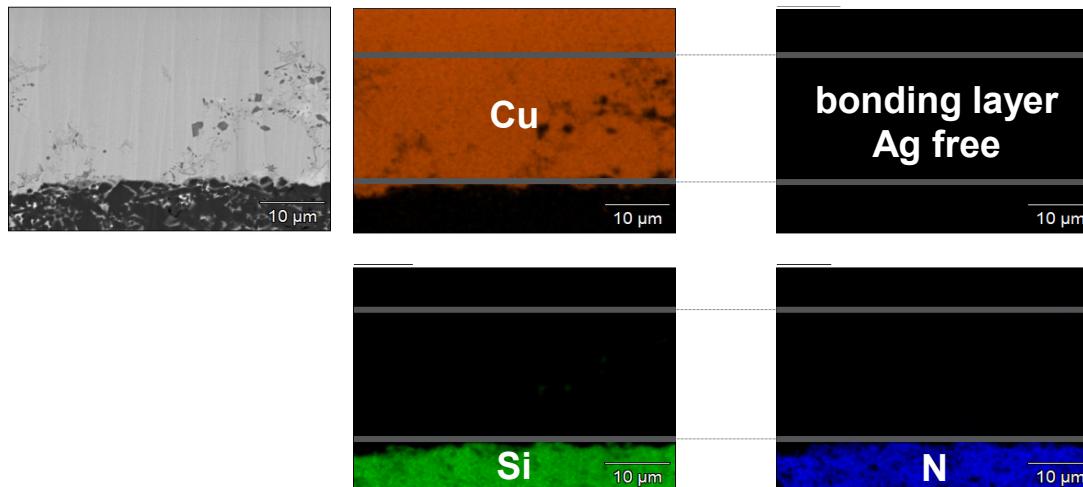
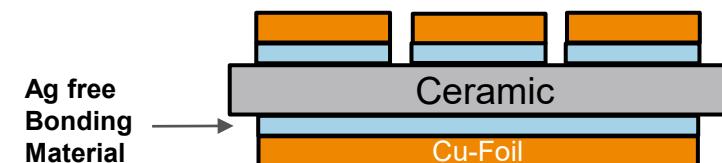
AMB STANDARD

- Typical AMB brazing pastes contain >60 weight % Ag



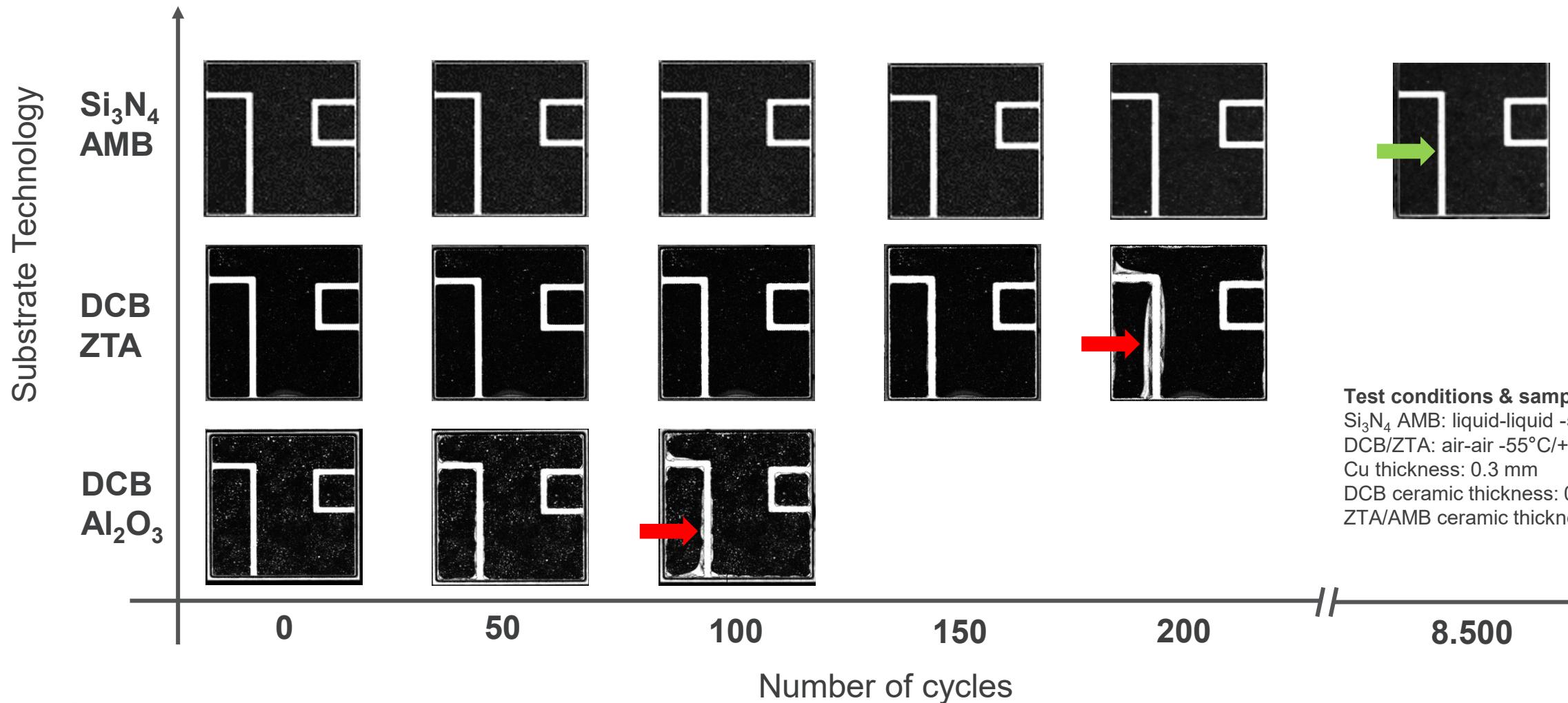
NEW BONDING TECHNOLOGY

- Bonding material is **Ag-free**
Effect: reduce costs / avoid Ag-migration



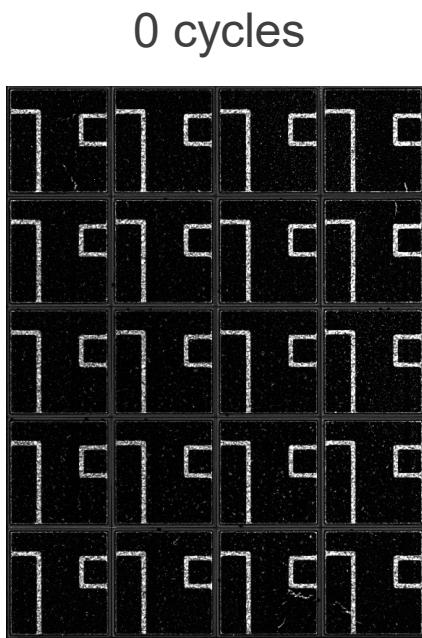
Source: Challenges of New Packaging Solutions for Power Modules, Prof. R. Eisele FH Kiel, Anton Miric HDE, PCIM Conference May 2021

SAM EVALUATIONS OF VARIOUS MCS TYPES AFTER THERMAL CYCLING



THERMAL SHOCK PERFORMANCE OF Si_3N_4 Ag FREE AMB

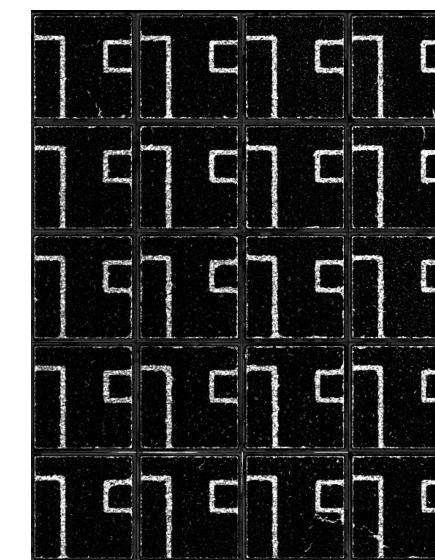
SAM measurements



0 cycles

1000 cycles

5000 cycles



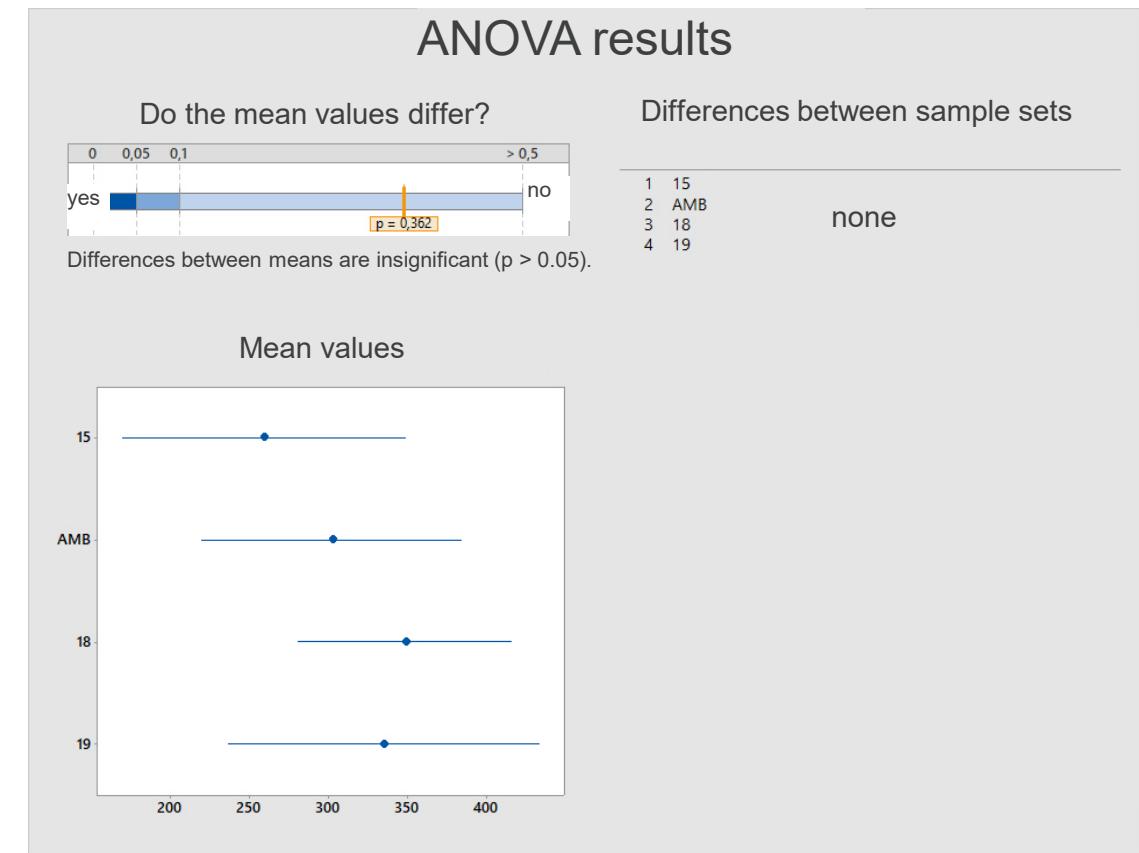
Conclusion

- No major degradation until 5000 cycles thermal shock observed.
- Si_3N_4 Ag free AMB is suitable for high reliability applications.

Material combination: 0.5 mm Cu & 0.32 mm Si_3N_4 ceramic
Test condition: -55°C/+150°C, 5 min dwell time

POWER CYCLING: COMPARISON STANDARD AND AG FREE AMB

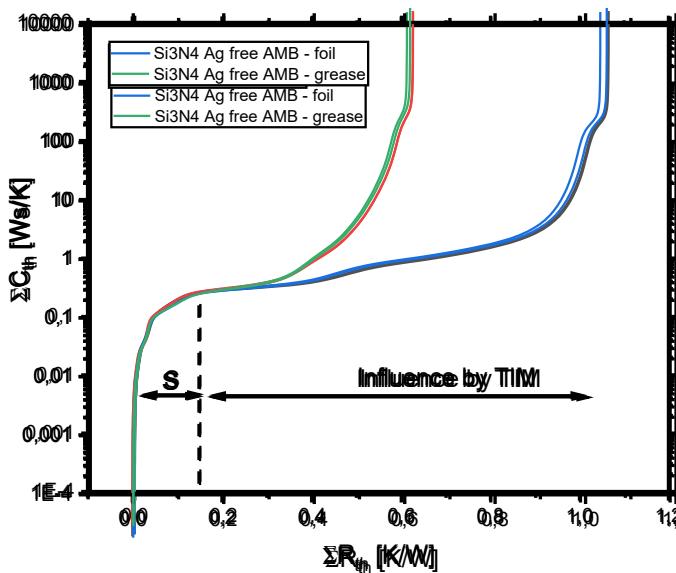
- IISB layout (0.5 / 0.32 / 0.5)
- Die (SKCD81) sintered with ASP338-28, based plate soldered
- CucorAL 0,3mm;
- $dT=85K$; P_{cmin} (ton 7 s)
- **No significant difference observed in power cycling compared with standard AMB**



Si_3N_4 Ag FREE AMB – THERMAL PERFORMANCE – R_{th} ASSESSMENT

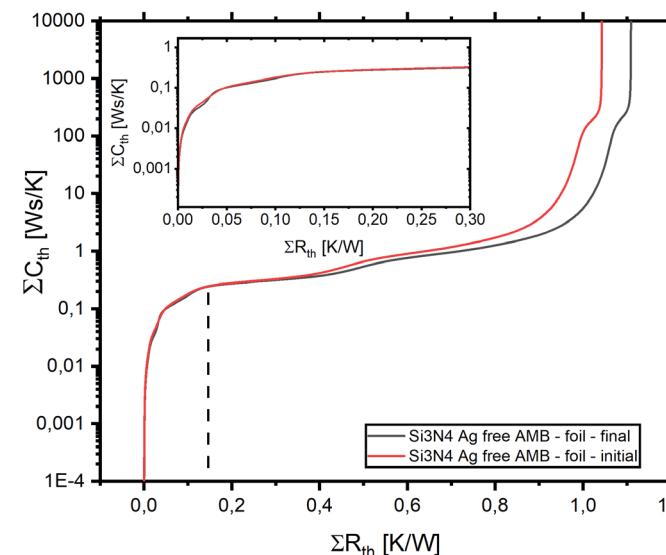
Initial status - R_{th}

- R_{th} assessed by Transient Dual Interface methodology.
- Cooling curve measurement of MCS with sintered diode and different TIMs.
- Point of divergence indicates R_{th} of assembly without TIM.



After HTS - R_{th}

- Substrates were aged by high temperature storage (HTS)
 - 1000h
 - 175°C

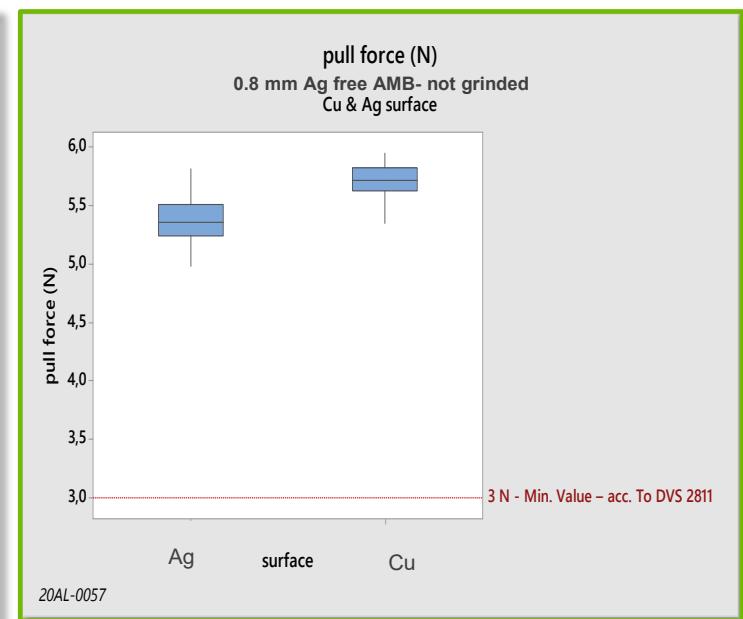
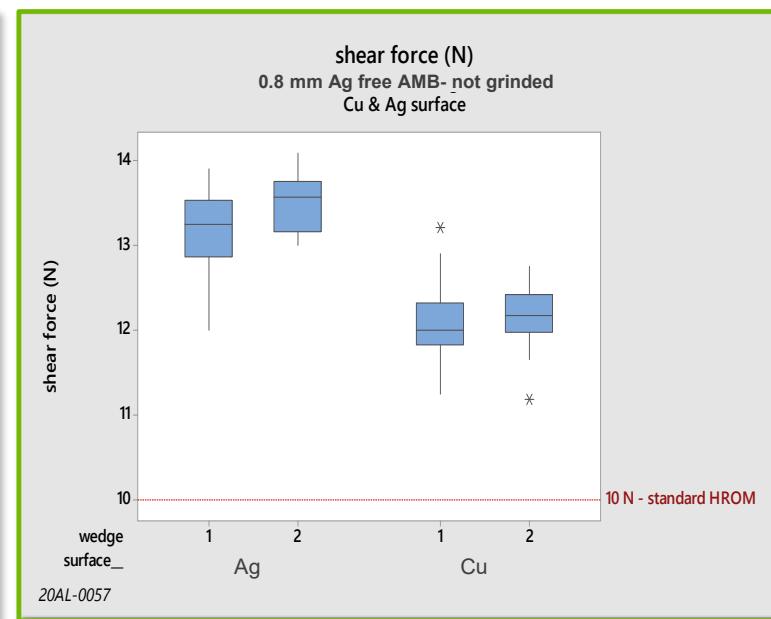
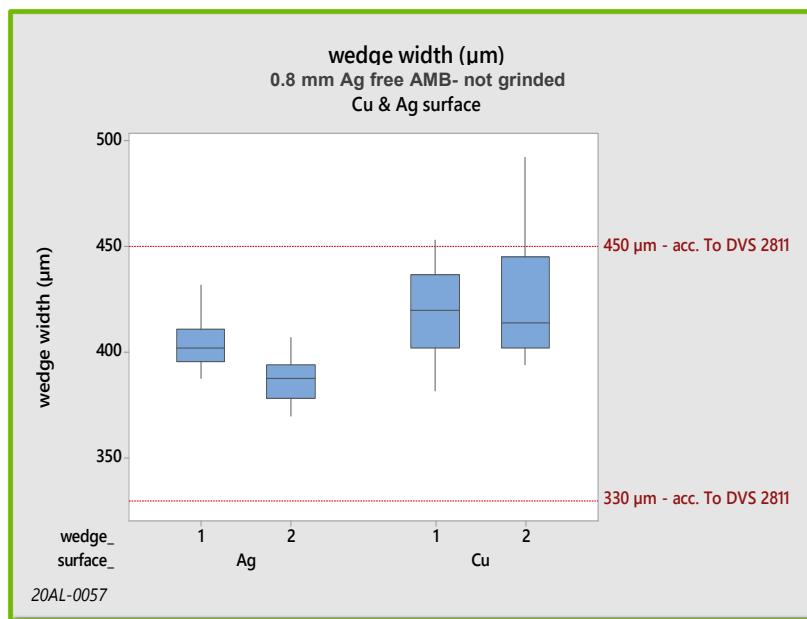


Conclusion

- No difference in R_{th} between our reference Si_3N_4 AMB and Si_3N_4 Ag free AMB.
- HTS does not induce a change in R_{th} on Si_3N_4 Ag free AMB substrates.

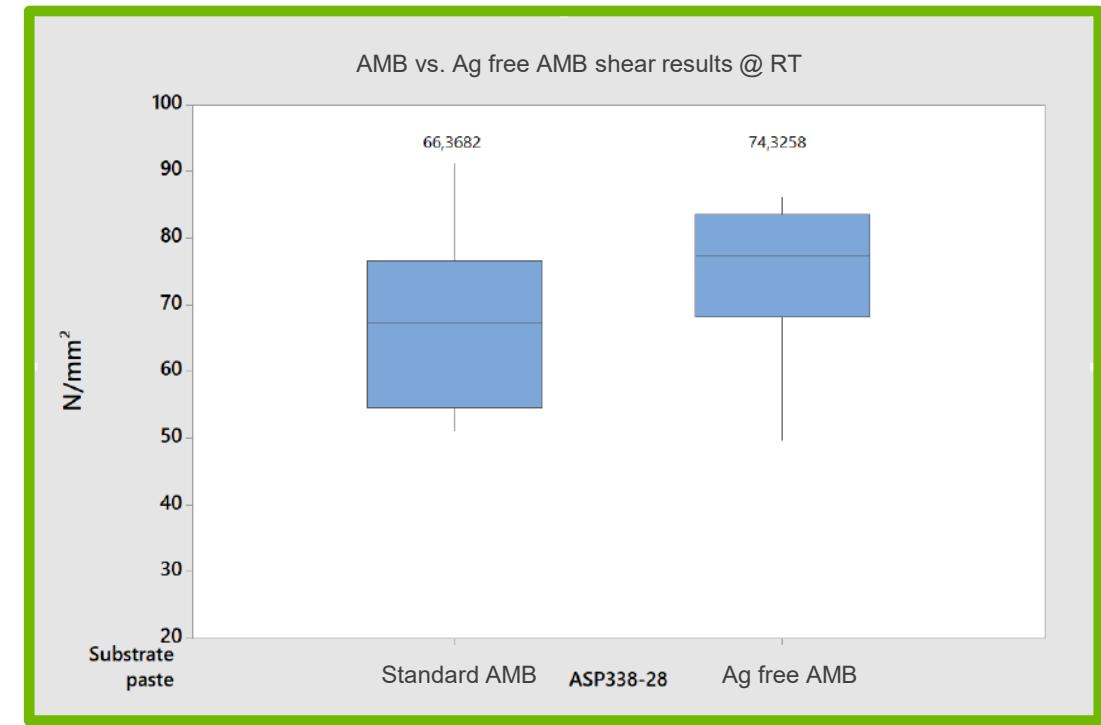
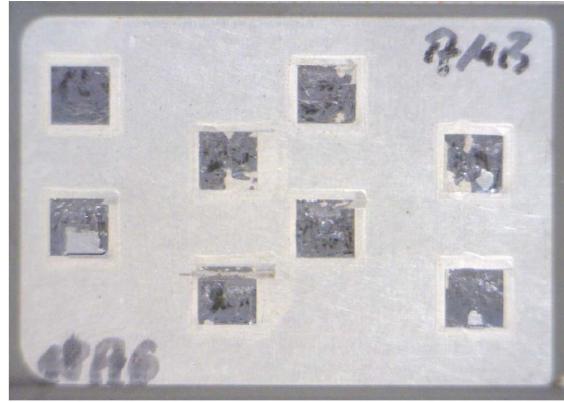
Si₃N₄ Ag FREE AMB – WIRE BONDABILITY

- IISB layout (0.5 / 0.32 / 0.5)
- Wire: 300µm Al-H11
- Tool: 127 153 - 12B Standard
- Shear test (XYZTEC) 1000µm shear tool / Pull test (XYZTEC) 600µm hook
- **All in spec**



Si₃N₄ Ag FREE AMB – SINTERABILITY

- IISB layout (0.5 / 0.32 / 0.5)
- Paste: ASP338-28
- Diode: SKCD16 (4x4x0.24 mm) Ag metallization
- Pressure: 20 MPa; Time 5 min
- **No significant difference observed compared with AMB in shear force and failure mode (mixed failure mode).**



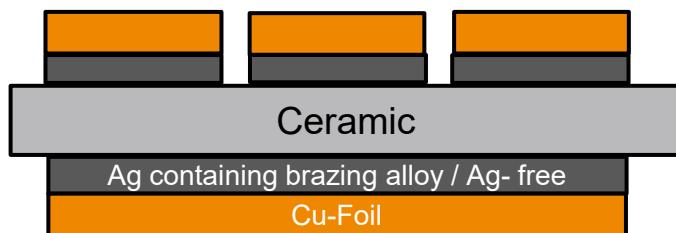
FINAL COMPARISON MCS SUBSTRATE PORTFOLIO

	Al ₂ O ₃ Condura®.classic	ZTA Condura®.extra	Si ₃ N ₄ Condura®.prime	Si ₃ N ₄ (80W/mK) Condura®.ultra	Si ₃ N ₄ (60W/mK) Condura®.ultra
Thermal conductivity	+-	+-	++	++	+
Bonding process (Cu)	DCB	DCB	AMB	AMB Ag free	AMB Ag free
Substrate reliability	+-	+	+++	+++	+++
Cu layer thickness	-	+-	+++	+++	+++
Substrate cost	+++	++	-	+-	+

DCB: Direct copper bonding



AMB: Active metal brazing



Source:

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CONDURA®.ULTRA Si₃N₄ AG FREE AMB PRODUCT TIMELINE AND AVAILABILITY

Samples
available

NOW !

Qualification

2022

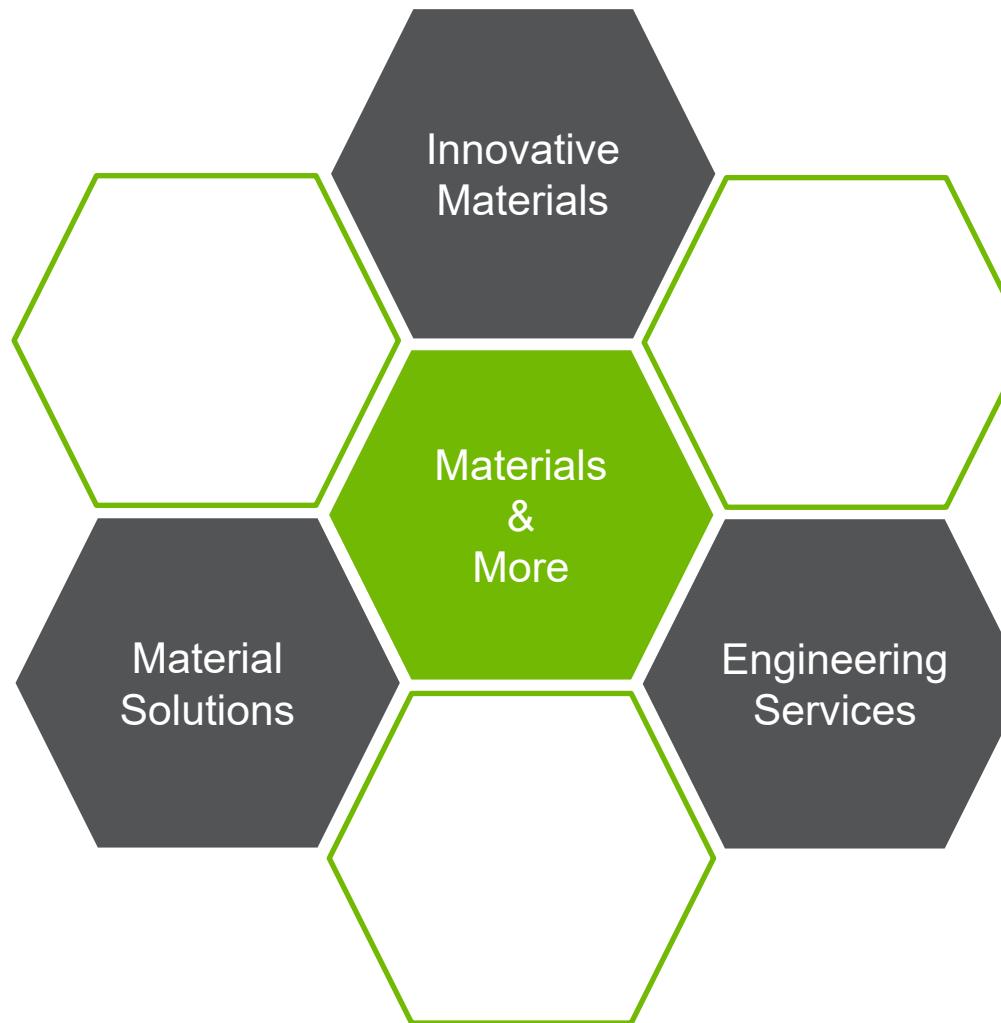
SOP

2023

SUMMARY

Si_3N_4 Ag free AMB fully leverages the advantages of the highly reliable Si_3N_4 ceramics:

- Si_3N_4 Ag free AMB shows similar thermal cycling capability as AMB
- No difference in R_{th} vs Si_3N_4 AMB
- No influence by HTS
- No risk of Ag migration
- Same processability as Si_3N_4 AMB (confirmed by lead customers)



Thank you for your attention.
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